



US00D789225S

(12) **United States Design Patent**  
**Teranishi et al.**

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(54) **PROBE PIN**

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(\*\*) Term: **15 Years**

(21) Appl. No.: **29/573,410**

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(30) **Foreign Application Priority Data**

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(52) **U.S. Cl.**  
USPC ..... **D10/80**

(58) **Field of Classification Search**

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CPC G01R 1/067; G01R 1/06705; G01R 1/06711;  
G01R 1/06716; G01R 1/06722; G01R  
1/06727; G01R 1/06733; G01R 1/06738;  
G01R 1/06744; G01R 1/0675; G01R  
1/06766; G01R 1/06772; G01R 1/06777;  
G01R 1/06783; G01R 1/0678

See application file for complete search history.

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(57) **CLAIM**

The ornamental design for a probe pin, as shown.

**DESCRIPTION**

FIG. 1 is a front, top, and right side perspective view of a probe pin showing our new design; FIG. 2 is a front view thereof; FIG. 3 is a rear view thereof; FIG. 4 is a left side view thereof; FIG. 5 is a right side view thereof; FIG. 6 is a top view thereof; and, FIG. 7 is a bottom view thereof.

**1 Claim, 5 Drawing Sheets**

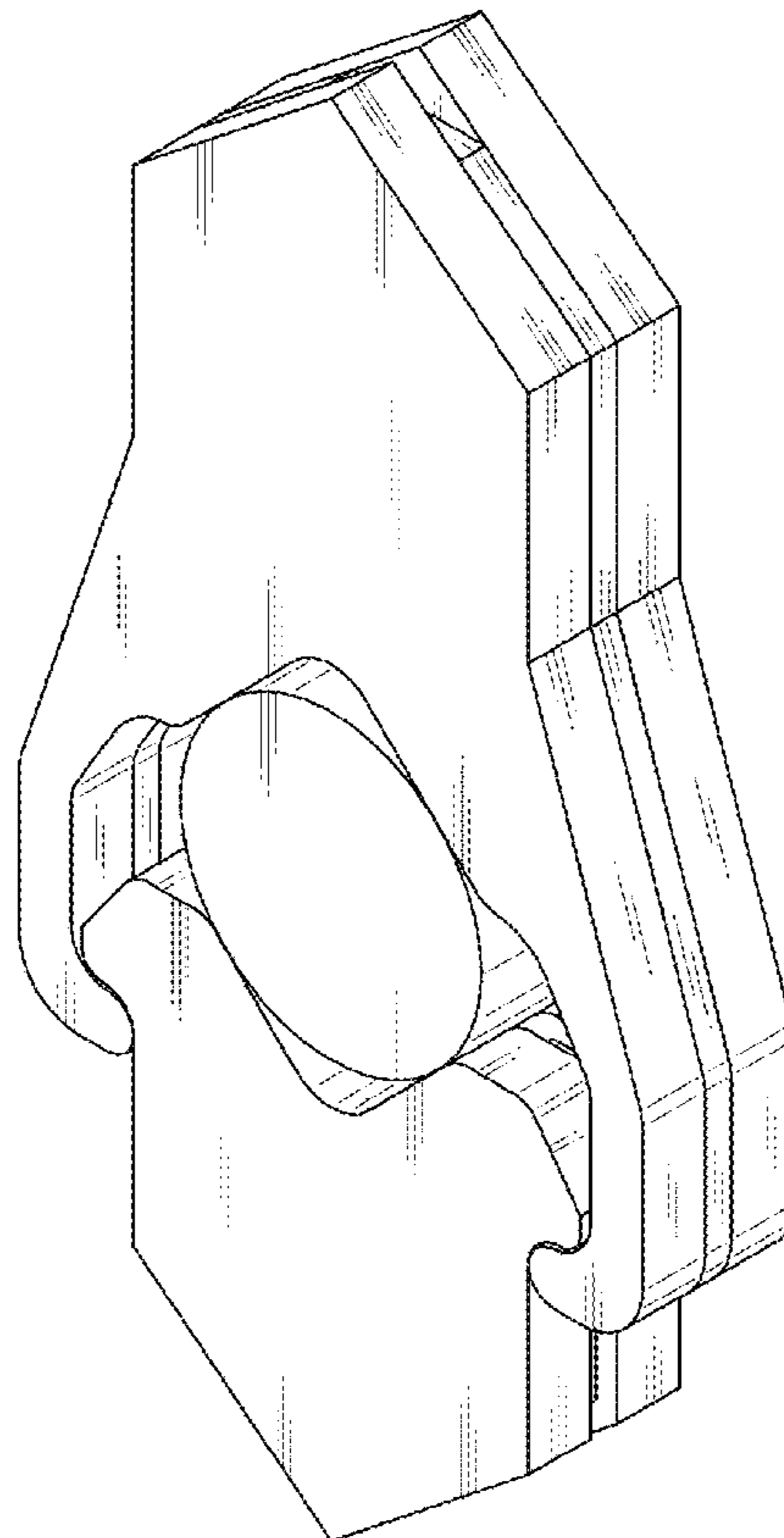


Fig. 1

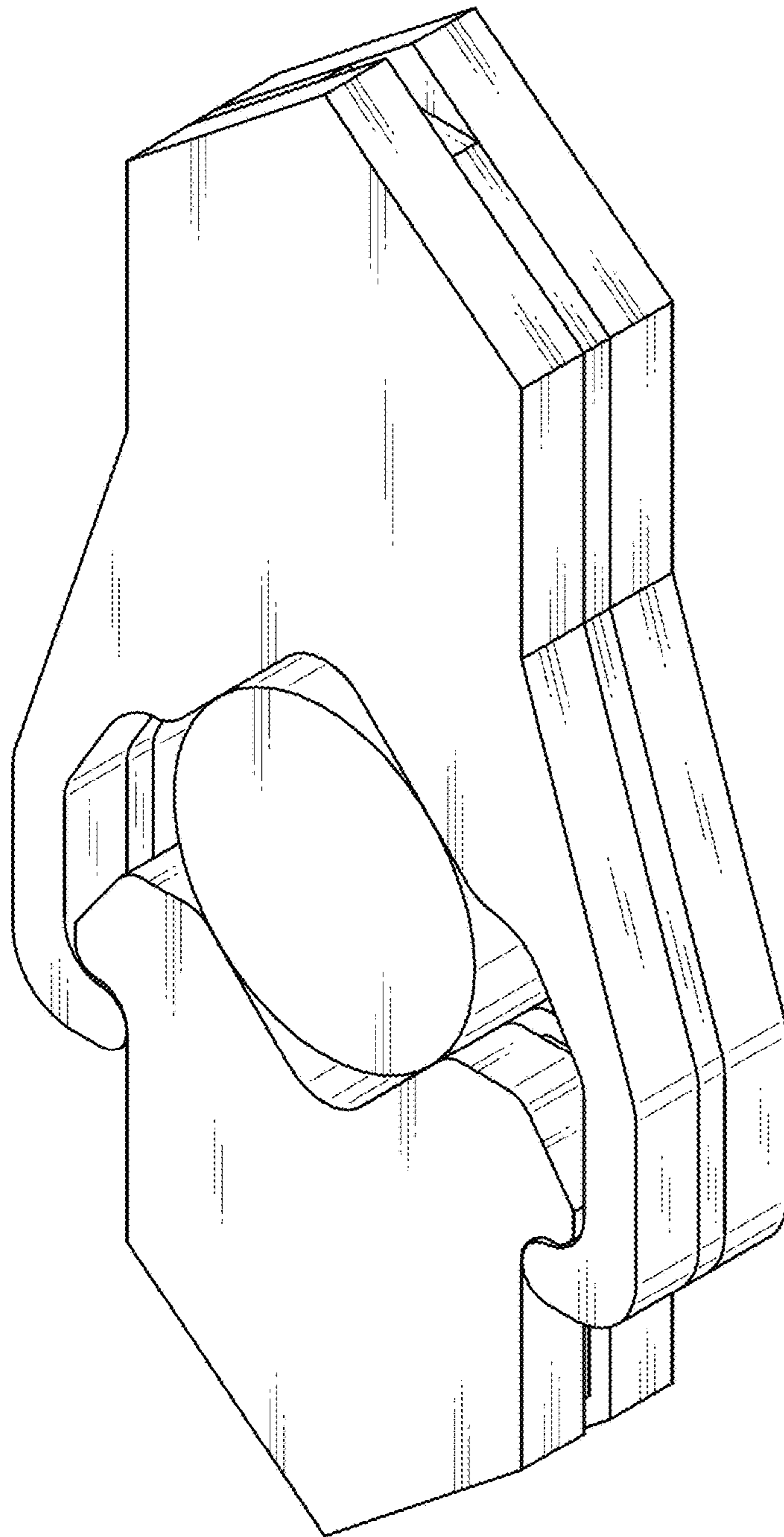


Fig. 2

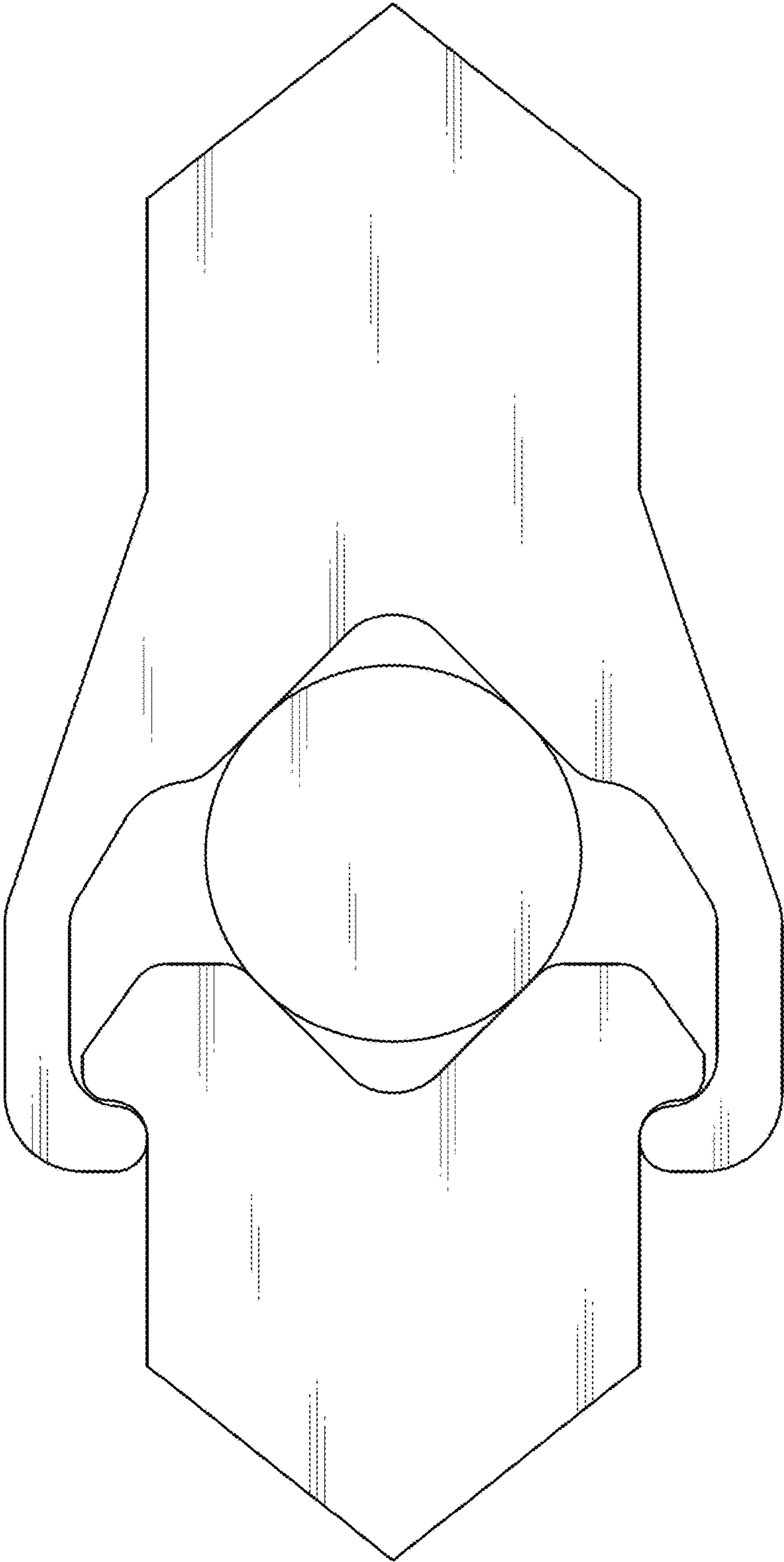


Fig. 3

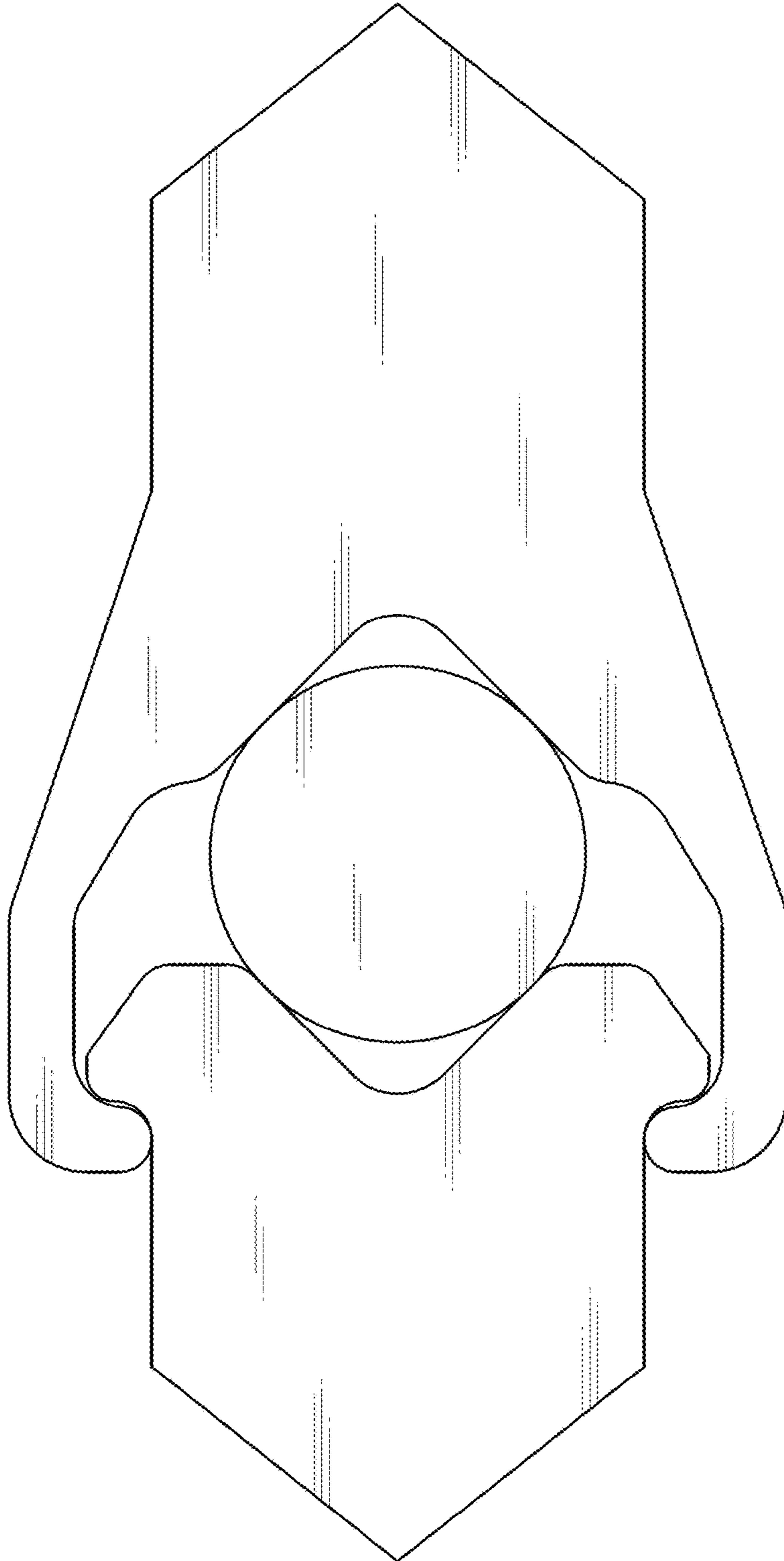


Fig. 4

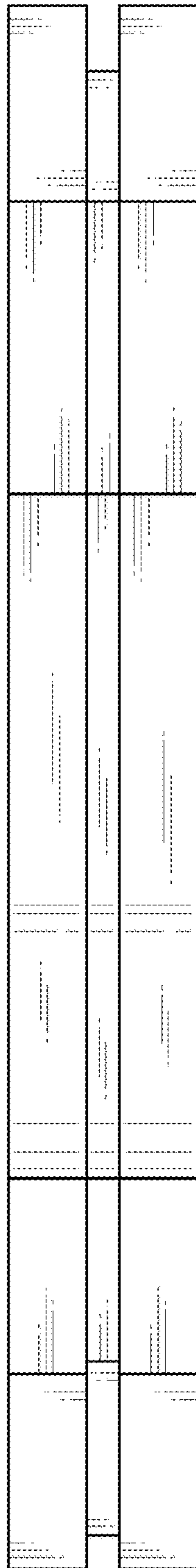


Fig. 5

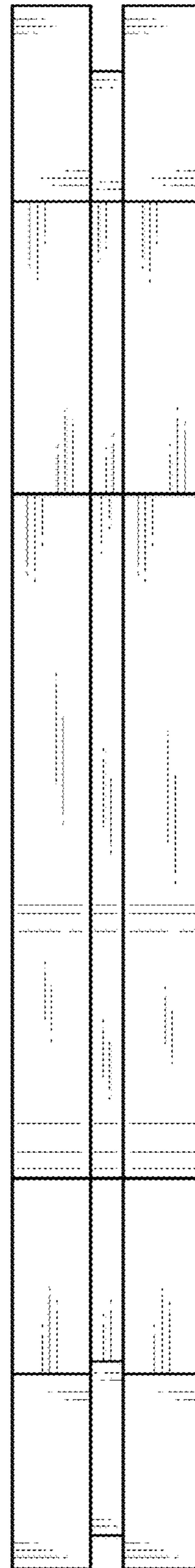


Fig. 6

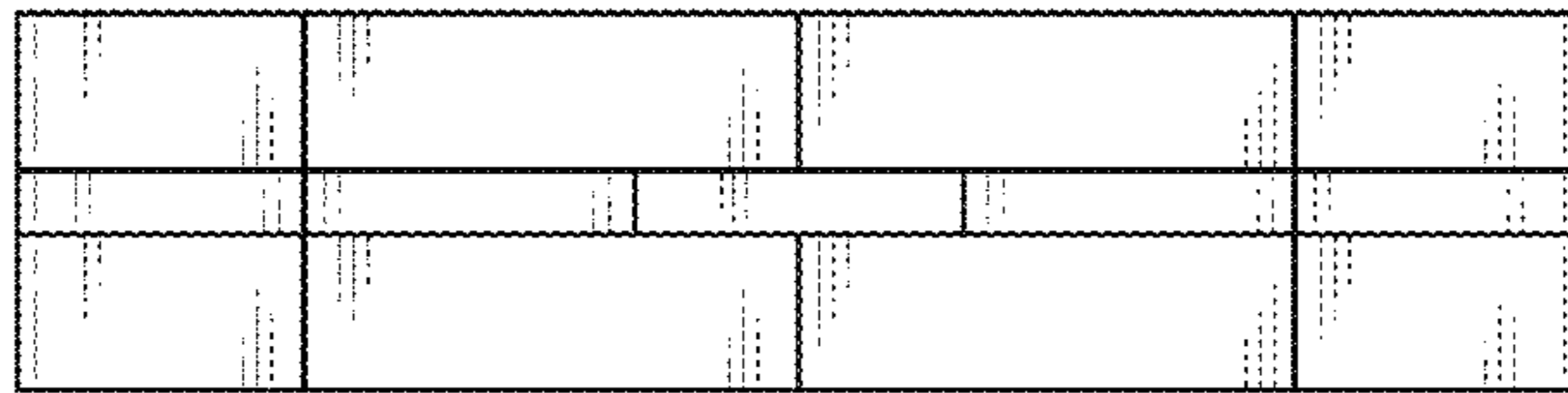


Fig. 7

